

Transaction Information

ToolId	92H8429AG (SA4A_B)
ToolStatus	Connected Idle
Location	Burlington
WaferSize	NA
FabSection	Test

General Product Information

VendorSupplier	MCC
Model	ABES V
Vintage	2001
SerialNo	6001 (M-312)
AssetDescription	BI tool (ambient / high temp only)
SoftwareVersion	
CIM	
Process	Burn-in

Hardware Configuration (Fab)

SystemType	Description	Quantity	Status
Main System	See description manual attached in addtl config files section.		OK
Factory Interface	NONE		OK
Handler System	n/a		OK
Options System			OK
Others			OK
Others			

Hardware Configuration (Subfab / Auxilliary Units)

Description	Quantity	Status
NONE		OK

Missing/Faulty Parts / Accesories List

Description	Quantity
None	

Tool Pictures

hardwaresubfab	n/a
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No Picture

general	tool pics
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manufactureserial

s/n plate



general

tool pics



missingparts	NONE
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No Picture

hardwarefab	See attached image
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Table 1-1. Main Features of the ABES-V

- Large burn-in boards with 20.5" x 21.7" user space
- ASIC architecture for per-pin timing, testing, and formatting
- Programmable system rep-rates up to 10 MHz (100 ns cycle time)
- Up to 256 I/O signals per burn-in board
- Large system capacity (32 burn-in boards)
- Timing on the fly
- Programmable clock edges with 1-nanosecond edge resolution
- Programmable rep-rate with 10-nanosecond resolution
- Up to 64 M vector memory words
- 2 K deep real-time error log
- 12 vector formats per pin per cycle
- Instruction stack depth of 16
- Up to 130 amps of programmable power to the devices under test (five separate voltages to each burn-in board)
- Easy-to-use **Breez-MZ™** software
- Architectural support for efficient generation of complex patterns for memory array testing
- Optional high-power burn-in (up to 20-watt devices)
- Optional programmable analog function generators

Additional Configuration Files